NAPSON CORPORATION

CALTRON PTE LTD

www.caltron.sg email: admin@caltron.sg

RG-2000AL (RG-3000AL) FULLY-AUTO SHEET RESISTANCE/RESISTIVITY MEASUREMENT

RG-2000AL(RG-3000AL)

- Fully automatic system with one cassette station
- Multi-point, Contact Type using 4-point probe method
- Widest measuring range and High accuracy
- User programmable measurement pattern
- Tester self-test function
- Thickness, edge, temperature correction for silicon wafer
- Film thickness conversion function from sheet resistance
- Measure Range:
  - ✓ Resistivity (Ω.cm): 0.1m to 1M
  - ✓ Sheet Resistance (Ω/sq): 1m to 10M
- Sample Size (Ø): 6", 8" or 12"

APPLICABLE MATERIALS

- Semiconductor and Solar-cell materials (Silicon, Polysilicon, SiC etc)
- Others: On Request